

Feature

- 100% EAS Guaranteed
- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

Product Summary

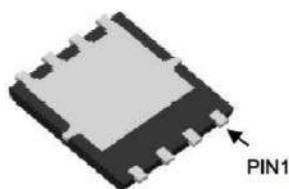


V_{DS}	30	V
$R_{DS(on),typ}$ $V_{GS}=10V$	4.8	$m\Omega$
I_D	55	A

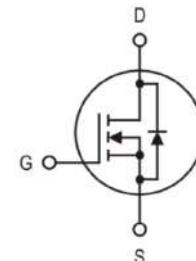
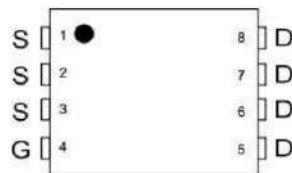
Application

- Power Management in Inverter System

top view



DFN3.3*3.3-8



Maximum ratings, at $T_A=25^{\circ}\text{C}$, unless otherwise specified

Symbol	Parameter	Rating	Unit
$V_{(BR)DSS}$	Drain-Source breakdown voltage	30	V
I_s	Diode continuous forward current	$T_c=25^{\circ}\text{C}$	A
I_D	Continuous drain current @ $V_{GS}=10V$	$T_c=25^{\circ}\text{C}$	A
		$T_c=100^{\circ}\text{C}$	A
I_{DM}	Pulse drain current tested ①	$T_A=25^{\circ}\text{C}$	A
EAS	Avalanche energy, single pulsed ②	105	mJ
P_D	Maximum power dissipation	$T_c=25^{\circ}\text{C}$	W
V_{GS}	Gate-Source voltage	± 20	V
MSL		Level 3	
T_{STG}, T_J	Storage and junction temperature range	-55 to 150	$^{\circ}\text{C}$

Thermal Characteristics

Symbol	Parameter	Typical	Unit
$R_{\theta JL}$	Thermal Resistance, Junction-to-Lead	40	$^{\circ}\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	70	$^{\circ}\text{C/W}$

Typical Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise stated)						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	30	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current($T_J=25^\circ\text{C}$)	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$	--	--	1	μA
	Zero Gate Voltage Drain Current($T_J=125^\circ\text{C}$)	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$	--	--	100	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	--	--	± 100	nA
$V_{GS(\text{TH})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0	1.5	2.5	V
$R_{DS(\text{ON})}$	Drain-Source On-State Resistance ③	$V_{GS}=10\text{V}, I_D=30\text{A}$	--	4.8	6	$\text{m}\Omega$
$R_{DS(\text{ON})}$	Drain-Source On-State Resistance ③	$V_{GS}=4.5\text{V}, I_D=20\text{A}$	--	7.5	12	$\text{m}\Omega$
Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise stated)						
C_{iss}	Input Capacitance	$V_{DS}=15\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$		3105		pF
C_{oss}	Output Capacitance			410		pF
C_{rss}	Reverse Transfer Capacitance			305		pF
R_g	Gate Resistance	$f=1\text{MHz}$	--	1.6	--	Ω
Q_g	Total Gate Charge	$V_{DS}=15\text{V}, I_D=15\text{A}, V_{GS}=10\text{V}$	--	31.6	--	nC
Q_{gs}	Gate-Source Charge		--	6.07	--	nC
Q_{gd}	Gate-Drain Charge		--	13.8	--	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=15\text{V}, I_D=20\text{A}, R_G=1.5\Omega, V_{GS}=10\text{V}$	--	11.2	--	nS
t_r	Turn-on Rise Time		--	49	--	nS
$t_{d(off)}$	Turn-Off Delay Time		--	35	--	nS
t_f	Turn-Off Fall Time		--	7.8	--	nS
Source- Drain Diode Characteristics@ $T_J = 25^\circ\text{C}$ (unless otherwise stated)						
V_{SD}	Forward on voltage	$I_{SD}=2\text{A}, V_{GS}=0\text{V}$	--	0.8	1.0	V
t_{rr}	Reverse Recovery Time	$T_J=25^\circ\text{C}, I_{sd}=10\text{A}, V_{GS}=0\text{V}$ $dI/dt=500\text{A}/\mu\text{s}$	--	20	--	nS
Q_{rr}	Reverse Recovery Charge			11.5		nC

NOTE:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by $T_{J\text{max}}$, starting $T_J = 25^\circ\text{C}$, $L = 0.1\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 42\text{A}$, $V_{GS} = 10\text{V}$. Part not recommended for use above this value
- ③ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.

Typical Characteristics

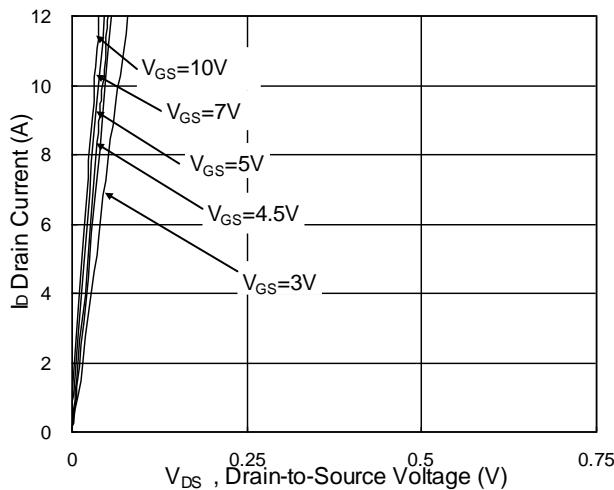


Fig.1 Typical Output Characteristics

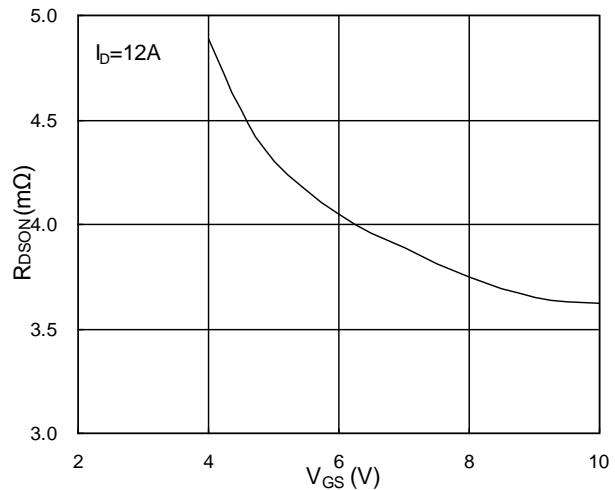


Fig.2 On-Resistance vs. G-S Voltage

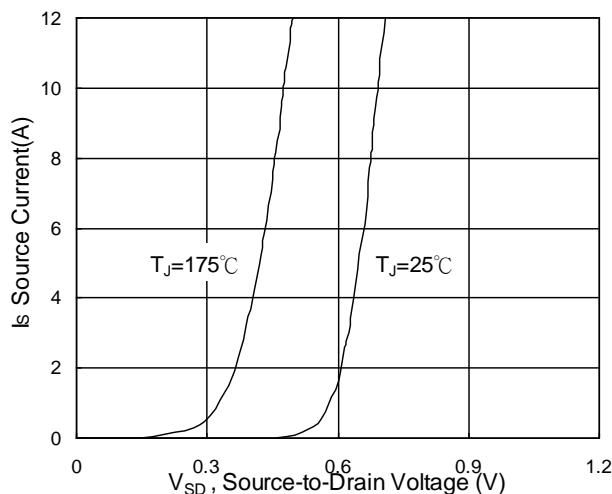


Fig.3 Forward Characteristics of Reverse

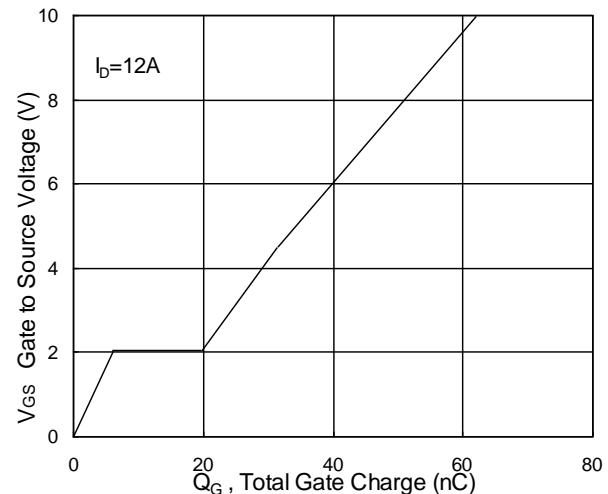


Fig.4 Gate-Charge Characteristics

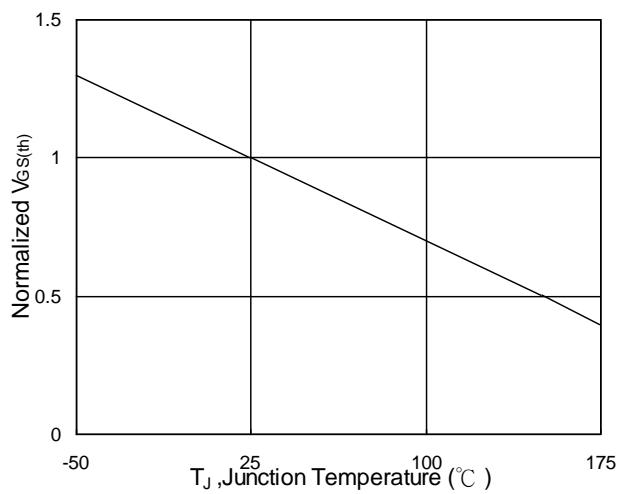


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

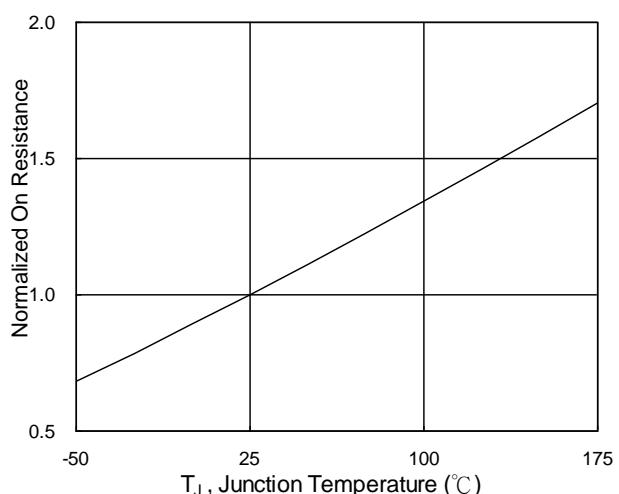


Fig.6 Normalized R_{DSON} vs. T_J

Typical Characteristics

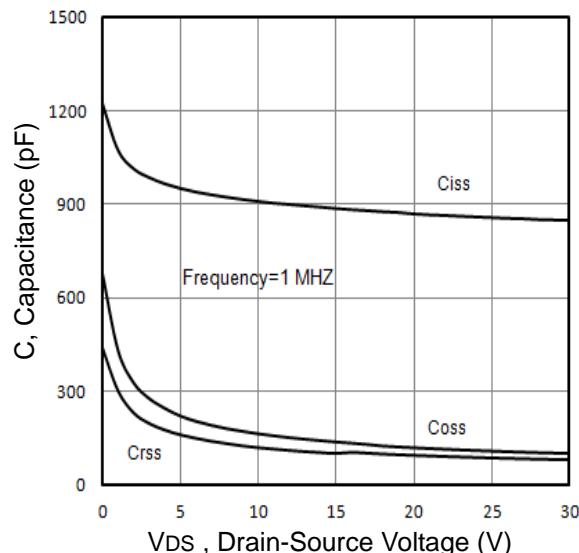


Fig7. Typical Capacitance Vs.Drain-Source Voltage

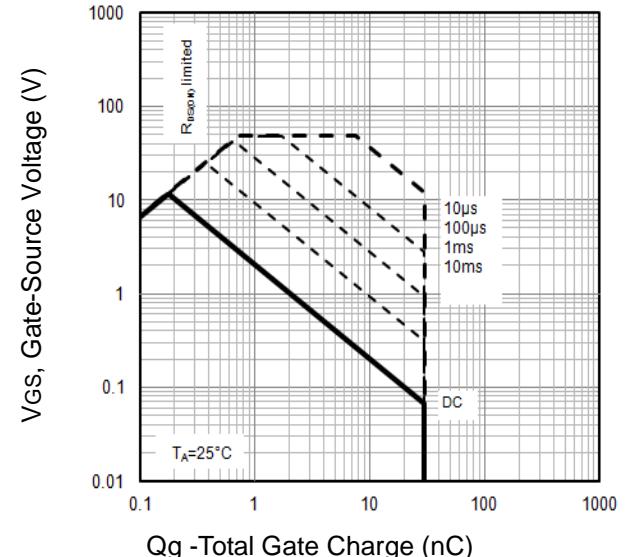


Fig8. Typical Gate Charge Vs.Gate-Source Voltage

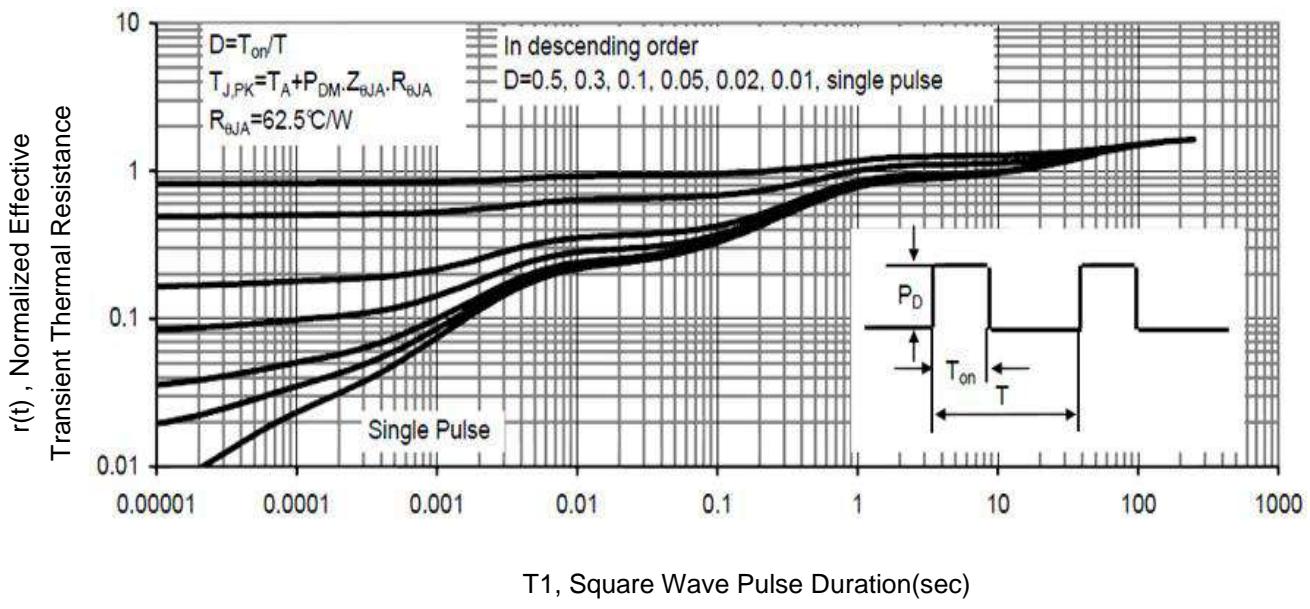


Fig9. T1 ,Transient Thermal Response Curve

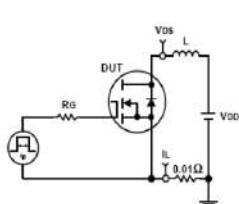


Fig10. Unclamped Inductive Test Circuit and waveforms

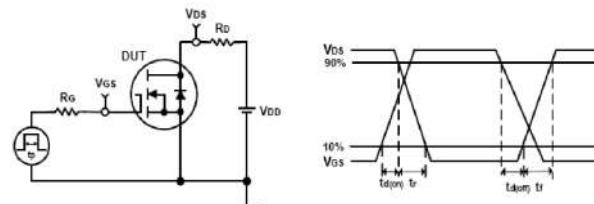
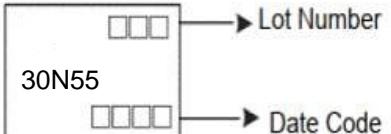


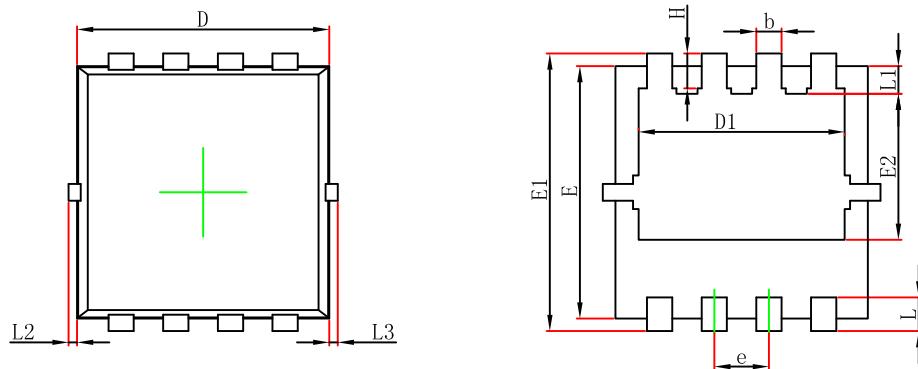
Fig11. Switching Time Test Circuit and waveforms

Ordering and Marking Information

Device	Marking	Package	Packaging	Quantity
JM3N30N55E-R	30N55	DFN3.3*3.3-8	Tape&Reel	5000

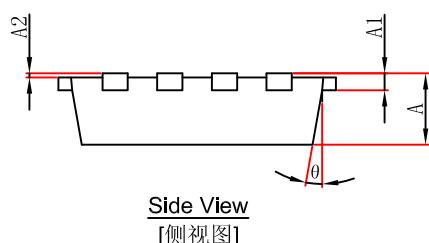
PACKAGE	MARKING
DFN3.3*3.3-8	 <p>The marking diagram shows a rectangular label with the part number "30N55" in the center. Above the part number, there are three small squares representing the Lot Number. Below the part number, there are four small squares representing the Date Code. Arrows point from these square groups to the labels "Lot Number" and "Date Code" respectively.</p>

DFN 3.3×3.3 -8 (P0.65T0.80) PACKAGE OUTLINE DIMENSIONS



Top View
[顶视图]

Bottom View
[背视图]



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
θ	9°	13°	9°	13°

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